

## **Search Notes**



**Application/Control No.**

10/608,095

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Examiner

Patricia Leith

**Applicant(s)/Patent under  
Reexamination**

TER LAAK ET AL.

## **Art Unit**

1655

**SEARCHED**

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**

## **INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner